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*van Exter, M.P.; Woerdman, J.P.;*  
Electronics Letters , Volume: 28 Issue: 17 , 13 Aug. 1992  
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Fault-Tolerant Computing, 1994. FTCS-24. Digest of Papers., Twenty-Fourth International Symposium on , 15-17 June 1994

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[\[Abstract\]](#) [\[PDF Full-Text \(736 KB\)\]](#) [IEEE CNF](#)**2 Evaluating the impact of the programming model on the performance complexity of software DSM systems***Seidel, C.B.; Bianchini, R.; Amorim, C.L.;*

Parallel Processing, 1999. Proceedings. 1999 International Conference on , 21-2 Sept. 1999

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